The MAJORANA DEMONSTRATOR Assay Program and Capabilities Necessary to Support a Future 1 Tonne Scale Experiemnt

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Top Level Table for Materials-MAJORANA

Material	Part of Demonstrator		Achieved Assay						
		Decay Chain	[µBq/kg]	[c/ROI/t/y]	Reference	[1] "Determination of Method Detection Limits for Trace			
	Inner Cu Shield,	Th	0.06	0.15		232-Thorium and 238-Uranium in Copper using Ion Exchange and ICPMS-January 2014". [M-TECHDOCPhys-			
EFCu	Cryostat, Coldplate, Thermal Shield, Detector Mounts	U	0.17	0.08	[1]	2014-72]. [2] Commercial Copper Assay Report[M-TECHDOCDET- 2012-149]			
	Outer Copper	Th	1.10	0.24	[2]	TECHDOCDET-2012-146]			
OFAC	Shield (O.Cut)	U	1.25	0.04					
DI-	Lead Shield	Th	<32	<1.5	[0]	[4] Final report on assay of plastic for MAJORANA DEMONSTRATOR [M-TECHDOCDET-2011-137].			
Pb		U	<112	<1.2	[3]				
PTFE	Detector	Th	$\textbf{0.1} \pm \textbf{0.01}$	0.01	[4 5]	[5] Report on NAA performed at HFIR (ORNL) for samples of TE-6742 for the MAJORANA DEMONSTRATOR [M-			
	Supports	U	<5	<0.01	[4,5]	TECHDOCDET-2011-128].			
DEEK	Cross Arm	Th	<1600	<0.01	[4 5]	[6] Cable Assay [M-TECHDOCDET-2011-124].			
PEEK	Support	U	<63000	<0.01	[4,5]				
Vespel	Cold Plate	Th	<12	<0.01	[4 5]	[7] ICP-MS of Low Mass Front-End Board; final [M- TECHDOCDET-2013-157]			
	Support	U	<1050	<0.01	[4,5]				
Damilana	Cu coating,	Th	2150	0.16	[6]	[8] ICP-MS Assay of MJD Copper Cables for Uranium &			
Parylene	Cryostat seals	U	3110	0.05	[6]	027].			
Silica /	Front-End	Th	6530	0.32	[7]	101 Service Pody Assey Posulta final IM TECHDOCDET			
Au, Epoxy	Electronics	U	10570	0.28	[7]	[5] Service Body Assay Results, Intal [M-TECHDOCDET- 2012-143]			
Cu Wire	Signal /HV Cable	Th	2.2	0.01	[0]				
+ PFA	and Connectors	U	145	0.14	[8]				
Stainless	Service Body	Th	13000	<0.04	[9]				
Steel		U	<5000	<0.03	L- J				

Top Level Table for Materials-MAJORANA

	Part of		Achieved			
Material	Demonstrator	Decay Chain	[µBq/kg]	[c/ROI/t/y]	Method	
	Inner Cu Shield,	Th	0.06	0.15		
EFCu	Cryostat, Coldplate, Thermal Shield, Detector Mounts	U	0.17	0.08	ICPMS	
05116	Outer Copper	Th	1.10	0.24		
OFHC	Shield (O.Cut)	U	1.25	0.04		
DI:		Th	<32	<1.5	CDMC	
PD	Lead Shield	U	<112	<1.2	GDIVIS	
	Detector	Th	$\textbf{0.1} \pm \textbf{0.01}$	0.01		
PIFE	Supports	U	<5	<0.01		
DEEK	Cross Arm	Th	<1600	<0.01		
PEEK	Support	U	<63000	<0.01	NAA	
Manual	Cold Plate	Th	<12	<0.01		
vespei	Support	U	<1050	<0.01		
Develope	Cu coating,	Th	2150	0.16		
Paryiene	Cryostat seals	U	3110	0.05		
Silica /	Front-End	Th	6530	0.32		
Au, Epoxy	Electronics	U	10570	0.28	ICPINS	
Cu Wire	Signal /HV Cable	Th	2.2	0.01		
+ PFA	and Connectors	U	145	0.14		
Stainless	Service Body	Th	13000	<0.04	GA	
Steel		U	<5000	<0.03		

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Copper Electroforming (EFCu)



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Production of EFCu

- 10 baths at the TCR in SURF
 - 1 bath now decommissioned Nov 2013
- 7 baths (out of 14) in PNNL underground
 - completing production for MJD in Jan 2014





Inspection of copper being electroformed at the TCR in SURF (above) and the shallow underground laboratory at PNNL (left)

MJD target of 0.3 μ Bq for both ²³²Th and ²³⁸U /kg Cu to meet equivalent of 1 count/ROI/t/y

Selecting Assay Techniques that Support Need



Sample: 24.23 kg OFHC Cu nuggets, 2009





ICP-MS at PNNL (1 week):

(thanks to M. Laubenstein)

- ⁴⁰K <500 μBq/kg
- 232 Th 1.3 ± 0.6 µBq/kg

GeMPI-2 at Gran Sasso

(4 month count or 8 kg-yr):

 40 K 190 ± 60 µBq/kg

 228 Th 30 ± 10 µBq/kg

 226 Ra 20 ± 10 µBq/kg

• ²³⁸U <30 μBq/kg

Combined results provides most useful information (2009):

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- ${}^{40}K$ 190 ± 60 μ Bq/kg
- 232 Th 1.3 \pm 0.6 μ Bq/kg
- 238 U 20 ± 10 µBq/kg

Current PNNL ICP-MS now (Jan 2013) sensitive to lower levels:

- ²³²Th ~0.7 μBq/kg
- ²³⁸U ~1.3 μBq/kg

Indirect Copper Purity Assay



In the absence of direct assays of copper with adequate sensitivity for U and Th, a simple model is produced to predict the concentration of these impurities based on the electrolyte assays. Based on this, MJD begins production electroforming in Sept 2010



Indirect Copper Purity Assay



Example of electrolyte replacement when contaminant levels reach the upper operating range Bath 3 TCR, first production run. PNNL has conducted over 300 electrolyte assays (as of Sept 2013) to track quality of the electroforming baths



Too much matrix (copper) issues during ICPMS analysis





X-lens

simply dissolve the sample prior to analysis and expect sensitivity desired for current experiments



Copper Assay Development



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- Completed the development of two methods at PNNL in 2013, electrochemical and ion exchange sample preparation, for trace assay of ²³²Th and ²³⁸U in copper
- ▶ Both have an MJD target of 0.3 µBq/kg Cu
 - Method Detection Limits for the electrochemical sample preparation (using PNNL produced Ir electrodes) followed by ICPMS have been determined on multiple occasions by one analyst with the best obtained being 0.10 µBq for both ²³²Th and ²³⁸U/kg Cu



Preparation of copper samples using the electrochemical method (above) and electrochemical electrodes (below)



U, Th background contributions-Electrochemical Sample Preparation





PNNL Activity: Copper Assay Development

- Method Detection Limits for the ion exchange sample preparation followed by ICPMS have been determined on multiple occasions by two analysts with the best obtained being 0.045 µBq ²³²Th and 0.098 µBq ²³⁸U/kg Cu
- Better sensitivity and sample throughput make the ion exchange method the primary analytical method. The electrochemical method will be used as a confirming method if deemed necessary.



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Preparation of copper samples using ion exchange methods in a laminar flow hood inside a class 10000 clean room



Example of electrolyte replacement when contaminant levels reach the upper operating range Bath 3 TCR, first production run. PNNL has conducted over 300 electrolyte assays (as of Sept 2013) to track quality of the electroforming baths





Other Assays to Consider: Evaluation of Physical Properties

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- Physical Property evaluation is comprehensive and performed for every production run
 - Important even if not producing your own material. Example, commercial OFHC copper mechanical strength can vary significantly
 - Multiple samples from various locations
 - Hardness mapping of every electroformed cross-section
 - Tensile strength
 - Crystal structure evaluation
 - Cross comparison of data to assure consistency of material



Above-Overlay of multiple tensile strength determinations on EFCu. Below-Crystal structure and hardness mapping overlay





Materials Assay



- ICP-MS assay on a wide variety of materials at PNNL
 - Assay cables and cable components, verification of new cable vendor performance
 - Polymer assays
 - Both of these use combustion in quartz furnace, microwave digestion (if necessary) followed by ion exchange
 - Continued assay of electrolyte from production baths to determine that Th and U levels maintained better than quality target levels used for inferred assays of Cu
 - Now performing assay of Pb using modification of copper ion exchange method to achieve greater sensitivity than GDMS





Left-Assay of polymers was challenged by the degradation of crucibles used for ashing Right-high purity copper is now used as the material of choice for ashing polymers

Analysis of High Purity Fused Silica and Front End Electronics

- Dissolve fused silica using HF in microwave digestor
- May also digest entire front end electronics board (FET, resistor, gold traces, etc. on fused silica wafer)
- Requires change-out of some ICP-MS components prior to HF use Assay detection limits for Th and U is μ Bq/kg, although materials not found that clean to date





Gamma Assay at LBC



The vacuum service body was assayed in the low background counting (LBC) lab at the Kimballton Underground Research Facility (KURF). Presented in this report are activities from detected isotopes, all of which are nuclides of naturally occurring radioactive materials (NORM) with the exception of ⁶⁰Co. It was found that ⁶⁰Co had the highest activity in the detector region, measuring 18.2 ± 1.0 mBq/kg.





NAA performed at HFIR (ORNL) of polymer samples



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- Polymer samples were analyzed via NAA analysis. A combination of irradiation at HFIR reactor, above ground fast counting at ORNL, and underground low background counting were used.
- Sample preparation remains a critical issue-contamination during initial sample preparation limited the method sensitivity, especially for Uranium detection.
- Upper limit of 1.15 pg ²³⁸U/g was set. ²³²Th was detected in the samples at a concentration of 0.025±0.002 pg/g.





Follow on NAA performed at HFIR (ORNL)



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Plastic	PTFE (TE-6742)	Vespel	PEEK	Kynar
²³⁸ U	<0.398 pg/g	<0.398 pg/g	<5.1 ng/g	1110 ng/g
²³² Th	0.025±0.002 pg/g	<2.9 pg/g	<0.4 ng/g	1.93 pg/g



GDMS on samples of Pb



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- Advantage is that many elements can be assayed at a time
- Samples needs to be electrically conductive (or made that way)
- Still 1-2 orders magnitude greater sensitivity desired

National Resea	arch Council Car	nada							
Institute for National Measurement Standards									
Analyst: B. Met	thven/K. Swider								
Glow Discharge Mass Spectrometric Report									
June 20, 2012									
To: Yuri Efremenko									
Oak Ridge National Laboratory									
NO. 32723									
ISO/IEC 17025									
Sullivan Pb, re	esults in ng/g								
1 H	2 Li <0.2	3 Be <0.08	4 B <0.1	5 C 180	6 N 3	7 O 200	8 F <0.5	9 Na 26	0 Mg <0.2
1 Al <0.2	2 Si 94	3 P <0.2	4 S 8	5 CI 18	6 K 4	7 Ca <2	8 Sc <0.1	9 Ti <0.05	0 V <0.04
1 Cr <0.2	2 Mn <0.1	3 Fe <0.1	4 Co <0.09	5 Ni 89	6 Cu 100	7 Zn <2	8 Ga <0.4	9 Ge <0.9	0 As <0.2
1 Se 110	2 Br <0.8	3 Rb <0.1	4 Sr <0.1	5 Y <0.09	6 Zr <0.2	7 Nb <0.09	8 Mo <0.5	9 Ru	0 Rh
1 Pd	2 Ag 12000	3 Cd 280	4 ln <0.3	5 Sn <1	6 Sb 10	7 Te <0.5	8 l <0.1	9 Cs <0.09	0 Ba <0.2
1 La <0.06	2 Ce <0.08	3 Pr	4 Nd	5 Sm	6 Eu	7 Gd	8 Tb	9 Dy	0 Ho
1 Er	2 Tm	3 Yb	4 Lu	5 Hf <0.3	6 Ta	7 W <0.4	8 Re	9 Os	0 Ir
1 Pt <0.9	2 Au <30	3 Hg <5	4 TI <140	5 Pb Matrix	6 Bi 400	7 Th <0.01	8 U <0.01		

Note: Due to the semi-quantitative capabilities of GD-MS, the determined mass fractions of impurities may lie in the range of one-half- to two-fold reported values except for C, N and O, for which the range is one-fifth- to five-fold.